

# SEMICONDUCTOR TECHNICAL DATA

### 2N3906S

#### EPITAXIAL PLANAR PNP TRANSISTOR

# GENERAL PURPOSE APPLICATION. SWITCHING APPLICATION.

#### **FEATURES**

- · Low Leakage Current
  - :  $I_{CEX}$ =-50nA(Max.),  $I_{BL}$ =-50nA(Max.)

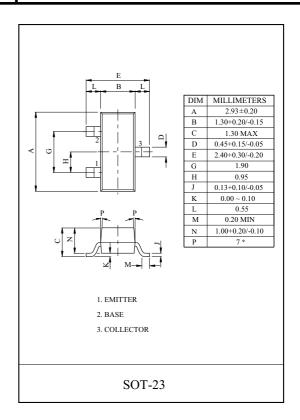
 $@V_{CE}=-30V, V_{EB}=-3V.$ 

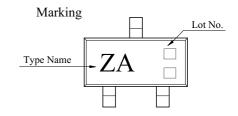
- · Excellent DC Current Gain Linearity.
- · Low Saturation Voltage
  - :  $V_{CE(sat)}$ =-0.4V(Max.) @ $I_{C}$ =-50mA,  $I_{B}$ =-5mA.
- · Low Collector Output Capacitance
  - :  $C_{ob}$ =4.5pF(Max.) @V<sub>CB</sub>=-5V.
- · Complementary to 2N3904S.

#### MAXIMUM RATING (Ta=25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	V <sub>CBO</sub>	-40	V
Collector-Emitter Voltage	V <sub>CEO</sub>	-40	V
Emitter-Base Voltage	V <sub>EBO</sub>	-5	V
Collector Current	$I_{C}$	-200	mA
Base Current	$I_{\mathrm{B}}$	-50	mA
Collector Power Dissipation	P <sub>C</sub> *	350	mW
Junction Temperature	T <sub>j</sub>	150	$^{\circ}$
Storage Temperature Range	$T_{stg}$	-55~150	$^{\circ}$

Note : \* Package Mounted On 99.5% Alumina  $10 \times 8 \times 0.6 \text{mm}$ )



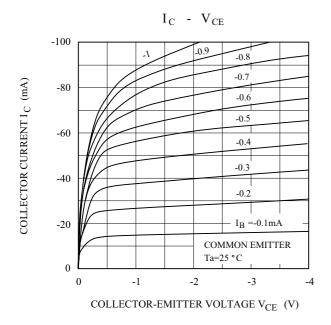


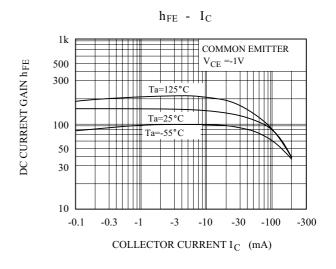
# 2N3906S

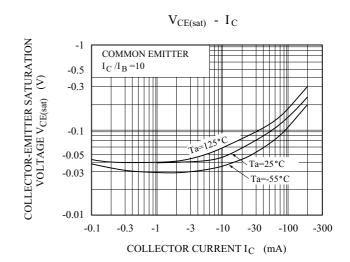
## ELECTRICAL CHARACTERISTICS (Ta=25 °C)

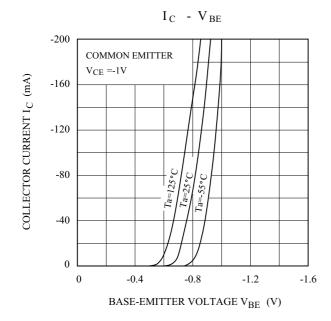
	III IC I LIUD I ICI	- (-	0)					
CHARAC	CTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Cu	rrent		I <sub>CEX</sub>	V <sub>CE</sub> =-30V, V <sub>EB</sub> =-3V	-	-	-50	nA
Base Cut-off Current	:		$I_{BL}$	V <sub>CE</sub> =-30V, V <sub>EB</sub> =-3V	-	-	-50	nA
Collector-Base Break	down Voltage		V <sub>(BR)CBO</sub>	$I_{C}$ =-10 $\mu$ A, $I_{E}$ =0	-40	-	-	V
Collector-Emitter Breakdown Voltage *		V <sub>(BR)CEO</sub>	$I_C=-1$ mA, $I_B=0$	-40	-	-	V	
Emitter-Base Breakdown Voltage *		V <sub>(BR)EBO</sub>	$I_{E}=-10\mu A,\ I_{C}=0$	-5.0	-	-	V	
DC Current Gain *			h <sub>FE</sub> (1)	V <sub>CE</sub> =-1V, I <sub>C</sub> =-0.1mA	60	-	-	
		h <sub>FE</sub> (2)	V <sub>CE</sub> =-1V, I <sub>C</sub> =-1mA	80	-	-		
		*	h <sub>FE</sub> (3)	V <sub>CE</sub> =-1V, I <sub>C</sub> =-10mA	100	-	300	
		h <sub>FE</sub> (4)	V <sub>CE</sub> =-1V, I <sub>C</sub> =-50mA	60	-	-		
			h <sub>FE</sub> (5)	V <sub>CE</sub> =-1V, I <sub>C</sub> =-100mA	30	-	-	
		V <sub>CE(sat)</sub> 1	$I_C$ =-10mA, $I_B$ =-1mA	-	-	-0.25	V	
Collector-Emitter Saturation Voltage		*	V <sub>CE(sat)</sub> 2	$I_C$ =-50mA, $I_B$ =-5mA	-	-		-0.4
Base-Emitter Saturation Voltage	*	V <sub>BE(sat)</sub> 1	I <sub>C</sub> =-10mA, I <sub>B</sub> =-1mA	-0.65	-	-0.85	V	
		V <sub>BE(sat)</sub> 2	$I_C$ =-50mA, $I_B$ =-5mA	-	-	-0.95		
Transition Frequency	7		$f_{\mathrm{T}}$	V <sub>CE</sub> =-20V, I <sub>C</sub> =-10mA, f=100MHz	250	-	-	MH
Collector Output Capacitance		C <sub>ob</sub>	$V_{CB}$ =-5V, $I_E$ =0, f=1MHz	-	-	4.5	pF	
Input Capacitance		C <sub>ib</sub>	V <sub>BE</sub> =-0.5V, I <sub>C</sub> =0, f=1MHz	-	-	10	pF	
Input Impedance		h <sub>ie</sub>	V <sub>CE</sub> =-10V, I <sub>C</sub> =-1mA, f=1kHz	2.0	-	12	kΩ	
Voltage Feedback Ratio		h <sub>re</sub>		1.0	-	10	x10	
Small-Signal Current Gain		h <sub>fe</sub>		100	-	400		
Collector Output Admittance		h <sub>oe</sub>		3.0	-	60	μδ	
Noise Figure		NF	$V_{CE}$ =-5V, $I_{C}$ =-0.1mA, Rg=1k $\Omega$ , f=10Hz $\sim$ 15.7kHz	-	-	4.0	dB	
Switching Time	Delay Time		t <sub>d</sub>	$V_{in}$ o $V_{out}$ $C_{in}$	-	-	35	
	Rise Time		t <sub>r</sub>	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	-	-	35	"c
	Storage Time		t <sub>stg</sub>	V <sub>in</sub> ο 10kΩ		-	225	nS
	Fall Time		$\mathbf{t_f}$	9.1V $-$ 0 $t_{\rm r}, t_{\rm f} < {\rm lns,  Du} = 2\%$	-	-	75	

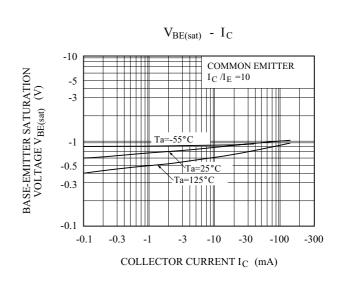
<sup>\*</sup> Pulse Test : Pulse Width  $\leq 300 \, \mu$ , Duty Cycle  $\leq 2\%$ .











3/4

